



भारतीय प्रौद्योगिकी संस्थान पटना

INDIAN INSTITUTE OF TECHNOLOGY PATNA

अनुसंधान एवं विकास इकाई
Research & Development Unit

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Date: 10/10/2019

Corrigendum in specification

This is with reference to our NIT Ref. No.: IITP/ R&D/364/FIST-03/2019-20 dated: 28.08.2019 and Tender ID- "2019_IITP_499657_1" for supply of "Multimode Scanning Probe Microscope for Imaging, Measurements and Device Testing".

Corrigendum 1.

ScanAsyst should be read as 'software to control all the AFM and STM modes measurement and analysis'. 'Peak force tapping and tapping mode' should be considered as a **single mode**.

Corrigendum 2.

AFM scanners with single piezoelectric tube

- Small scanner (~0.5 micron maximum scan range)
- Medium scanner (~10 micron maximum scan range)

Or

A single scanner for all the measurements and resolutions can be offered

Corrigendum 3.

Optional items: Vibration isolation table.

The specification should be read as 'vibration isolation table should be offered to achieve the best resolution of the quoted machine'.

Corrigendum 4.

Optional item: Large scanner (~125 micron)

May be integrated with the single scanner as mentioned in corrigendum 2.

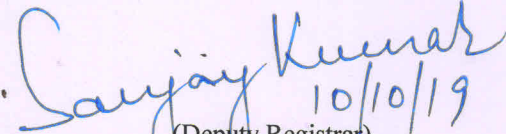
Corrigendum 5.

Vendor should quote the **latest model available** with them to meet the tender specifications.

The last date & time of Bid Submission has been extended till: 24/10/2019, 04:30 PM

Opening date & time of Technical Bids online : 25/10/2019, 04:00 PM

This is being issued with the approval of the Competent Authority.


Sanjay Kumar
(Deputy Registrar)
Deputy Registrar
IIT Patna, Bihta
Patna-801106

Copy to:

1. Associate Dean, R&D, IIT Patna
2. Dr. Alpana Nayak (PI)
3. Institute Website
4. Project file